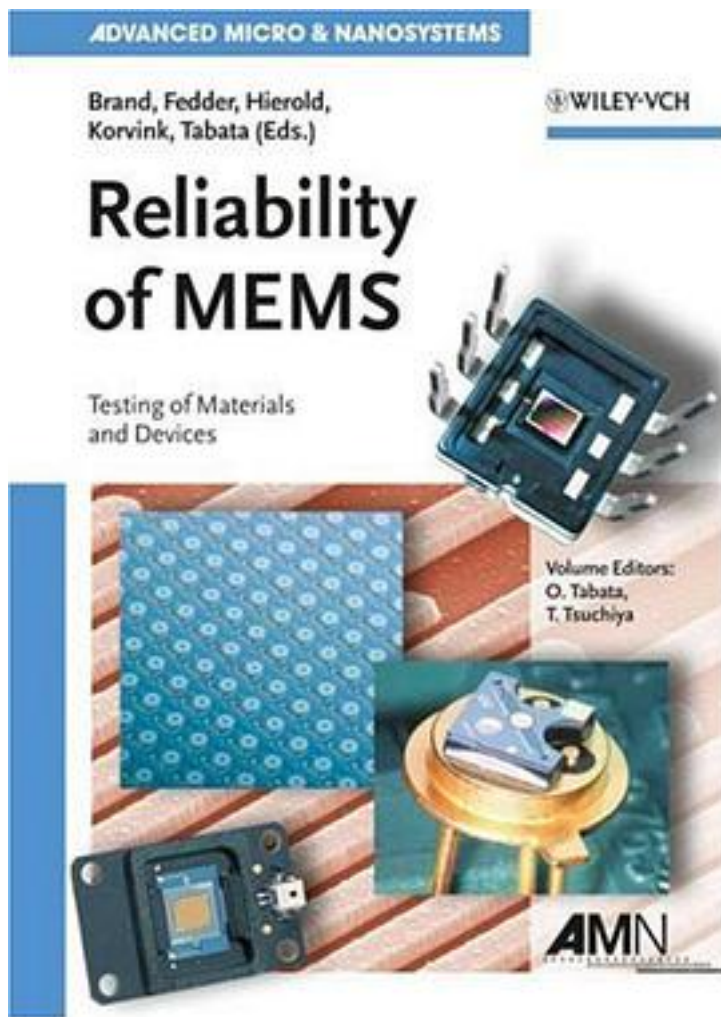


Reliability of Mems



[Reliability of Mems_ 下载链接1](#)

著者:Hierold, Christofer 编

出版者:John Wiley & Sons Inc

出版时间:

装帧:HRD

isbn:9783527314942

This first book to cover exclusively and in detail the principles, tools and methods for

determining the reliability of microelectromechanical materials, components and devices covers both component materials as well as entire MEMS devices. Divided into two major parts, following a general introductory chapter to reliability issues, the first part looks at the mechanical properties of the materials used in MEMS, explaining in detail the necessary measuring technologies -- nanoindenters, bulge methods, bending tests, tensile tests, and others. Part Two treats the actual devices, organized by important device categories such as pressure sensors, inertial sensors, RF MEMS, and optical MEMS.

作者介绍:

目录:

[Reliability of Mems_ 下载链接1](#)

标签

评论

[Reliability of Mems_ 下载链接1](#)

书评

[Reliability of Mems_ 下载链接1](#)